Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/539,012	CHO ET AL.	
Examiner	Art Unit	
Patrick T. Lewis	1623	

	SEAR	CHED	
Class	Subclass	Date	Examiner
	- "		
			-
			_
	11-		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		<u> </u>			
	1				

SEARCH (INCLUDING SEAR		ATEGY)
		ATE	EXMR
Inventor, REGISTRY	12/3	31/2007	PL
•			